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PATENT NUMBER and  
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10086214	FILING DATE 02/27/2002	CLASS 714	SUBCLASS 72.6	GAU 2484	EXAMINER Deady
<b>**APPLICANTS:</b> Wang Laung-Terng; Chang Ming-Tung; Lin Shyh-Horng; Chao Hao-Jan; Lee Jaehee; Wang Hsin-Po; Wen Xiaoping; Hsu Po-Ching; Kao Shih-Chia; Lin Meng-Chyi; Tsai Sen-Wei; Hsu Chi-Chan; 2132					
<b>**CONTINUING DATA VERIFIED:</b> THIS APPLN CLAIMS BENEFIT OF 60/272,064 03/01/2001					
<b>** FOREIGN APPLICATIONS VERIFIED:</b>					
PG-PUB DO NOT PUBLISH <input type="checkbox"/>		RESCIND <input type="checkbox"/>			
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no		ATTORNEY DOCKET NO			
35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no		3175-Z			
Verified and Acknowledged Examiners's initials					
TITLE : Method and apparatus for diagnosing failures in an integrated circuit using design-for-debug (DFD) techniques					
U.S. DEPT. OF COMM. / PAT. & TM. PTO-436 (Rev. 12-94)					

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<b>NOTICE OF ALLOWANCE MAILED</b>		<b>CLAIMS ALLOWED</b>	
		Total Claims	Print Claim for O.G.
<b>ISSUE FEE</b>		<b>DRAWING</b>	
Amount Due	Date Paid	Shots Drwg.	Figs. Drwg. Print Fig.
<input type="checkbox"/> <b>TERMINAL DISCLAIMER</b>		<b>Application Examiner</b>	
		<b>PREPARED FOR ISSUE</b>	
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